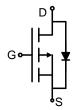


Main Product Characteristics:

V _{DSS}	-30V
R _{DS} (on)	19mΩ(typ.)
I _D	-25A ①







TO-252

Marking and pin
Assignment

Schematic diagram

Features and Benefits:

- Advanced trench MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V(Silicon Limited)	-25 ①	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	-20 ①	Α
I _{DM}	Pulsed Drain Current ②	-60	
P _D @TC = 25°C	Power Dissipation	41	W
V _{DS}	Drain-Source Voltage		V
V _{GS}	Gate-to-Source Voltage	± 20	V
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C

Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
R ₀ JC	Junction-to-case③	_	3	°C/W
В	Junction-to-ambient (t \leq 10s) (4)		25	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④		50	°C/W





Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	-30	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
D	Static Drain-to-Source on-resistance	I	19	35	mΩ	V_{GS} =-10 V , I_{D} = -6 A
R _{DS(on)}	Static Diam-to-Source on-resistance	I	29	58	11152	V _{GS} =-4.5V,I _D =-5A
V	Gate threshold voltage	-1.2	_	-2.4	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
$V_{GS(th)}$	Gate threshold voltage	_	-1.4	_	V	T _J = 125℃
I _{DSS}	Drain-to-Source leakage current	_	_	-1	μA	$V_{DS} = -24V, V_{GS} = 0V$
1	Cata to Source forward lookage	_	_	100	nA	V _{GS} =20V
I_{GSS}	Gate-to-Source forward leakage	_	_	-100	IIA	V _{GS} = -20V
Q_g	Total gate charge	_	27	_		I _D = -20A,
Q_{gs}	Gate-to-Source charge	_	3.6	_	nC	V _{DS} =-25V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	9.1	_		V _{GS} = -10V
t _{d(on)}	Turn-on delay time	_	10.7	_		
t _r	Rise time	_	39	_	~C	V _{GS} =-10V, V _{DS} =-15V,
t _{d(off)}	Turn-Off delay time	_	25.8	_	nS	$R_L=0.75\Omega, I_D=-20A$
t _f	Fall time	_	6.4	_		
C _{iss}	Input capacitance	_	1188	_		$V_{GS} = 0V$,
Coss	Output capacitance	_	173	_	pF	V _{DS} =-15V,
C _{rss}	Reverse transfer capacitance	_	139	_		f = 1MHz

Source-Drain Ratings and Characteristics

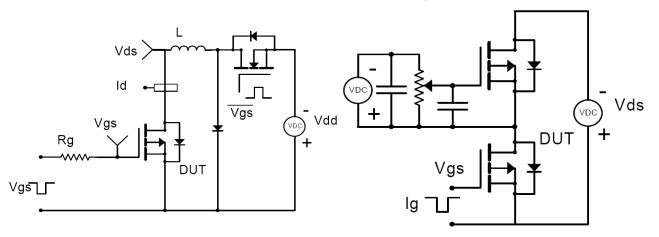
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current		_	-25 ①	А	MOSFET symbol
I _S	(Body Diode)	_				showing the
	Pulsed Source Current		_	-100	Α	integral reverse
I _{SM}	(Body Diode)					p-n junction diode.
V _{SD}	Diode Forward Voltage	_	-0.77	-1	V	I _S =-1A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	23	_	nS	$T_J = 25$ °C, $I_F = -20$ A, $di/dt =$
Q _{rr}	Reverse Recovery Charge	_	14	_	nC	100A/μs



Test circuits and Waveforms

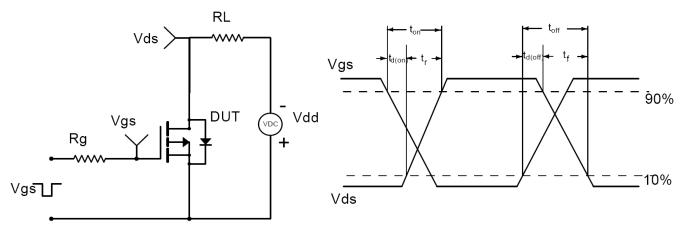
EAS test circuit:

Gate charge test circuit:



Switching time test circuit:

Switch Waveforms:

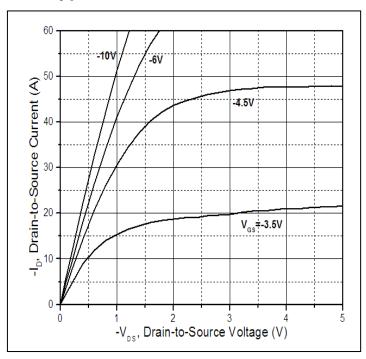


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max junction temperature.
- ③The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- 4 These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}=150$ °C.



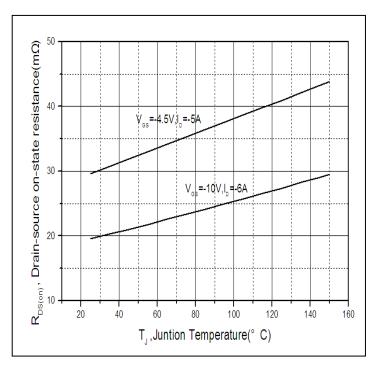
Typical electrical and thermal characteristics

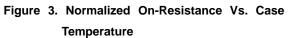


36.5 36.5 36.0

Figure 1: Typical Output Characteristics

Figure 2. Drain-to-Source Breakdown Voltage vs.
Temperature





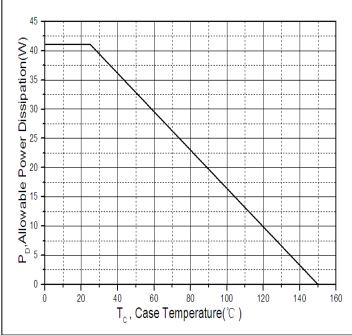
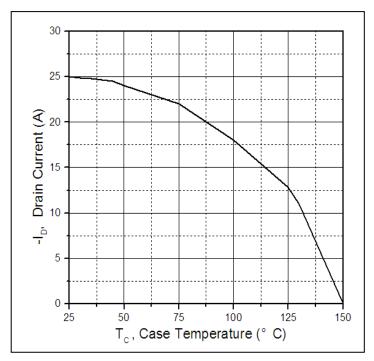


Figure 4: Power Dissipation Vs. Case Temperature



Typical electrical and thermal characteristics



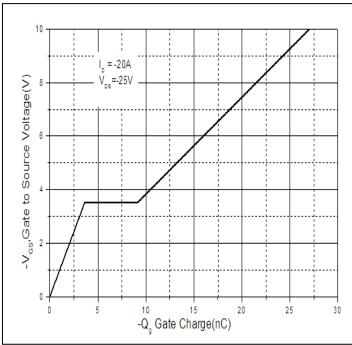


Figure 5. Maximum Drain Current Vs Case Temperature

Figure 6. Gate-Charge Characteristics

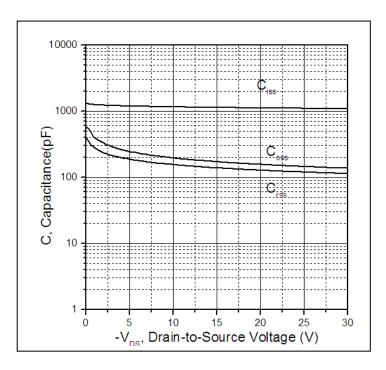


Figure 7. Typical Capacitance Vs. Drain-to-Source Voltage



Typical electrical and thermal characteristics

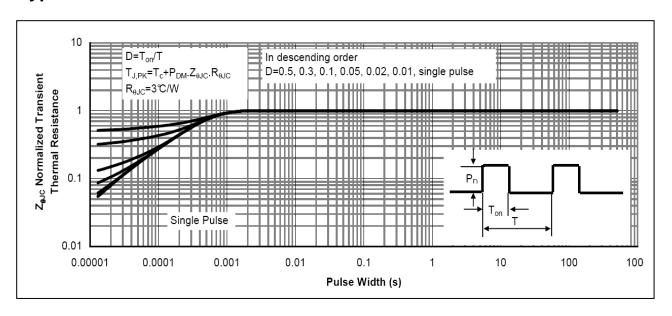
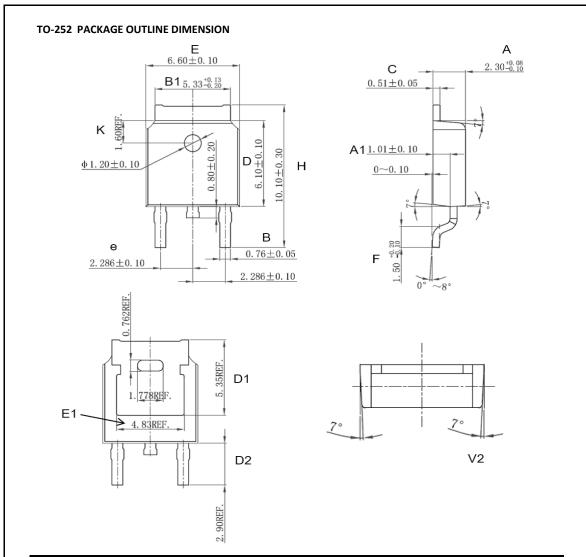


Figure 8. Normalized Maximum Transient Thermal Impedance



Mechanical Data:



Symbol	Dimension In Millimeters			Dimension In Inches		
	Min	Nom	Max	Min	Nom	Max
Α	2.200	2.300	2.380	0.087	0.091	0.094
A1	0.910	1.010	1.110	0.036	0.040	0.044
В	0.710	0.760	0.810	0.028	0.030	0.032
B1	5.130	5.330	5.460	0.202	0.210	0.215
С	0.460	0.510	0.560	0.018	0.020	0.022
D	6.000	6.100	6.200	0.236	0.240	0.244
D1		5.350 (REF)		0.211 (REF)		
D2		2.900 (REF)		0.114 (REF)		
E	6.500	6.600	6.700	0.256	0.260	0.264
E1		4.83 (REF)		0.190 (REF)		
е	2.186	2.286	2.386	0.086	0.090	0.094
Н	9.800	10.100	10.400	0.386	0.398	0.409
F	1.400	1.500	1.700	0.055	0.059	0.067
K	1.600 (REF)			0.063 (REF)		
V2		8 ⁰ (REF)			8 ⁰ (REF)	



Ordering and Marking Information

Device Marking: SSF4607D

Package (Available)
TO-252(DPAK)
Operating Temperature Range
C:-55 to 150 °C

Devices per Unit

Package	Units/	Tapes/Inner	Units/Inner	Inner	Units/Carton
Type	Tape	Box	Box	Boxes/Carton	Box
	_			Box	
TO-252	2500	1	2500	5	12500

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	Tj=125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /V _R	1000 hours	
Bias(HTRB)			
High	Tj=150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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